Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/539,870	IWAKI ET AL.
Examiner	Art Unit

Son T. Nguyen

3643

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Class	Subclass	Date	Examiner

ראו	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH (INCLUDING SEAR		)
	DATE	EXMR
previous search updated	7/10/2007	STN
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